Search Notes

Application/Control No.	Applicant(s)/Patent Reexamination	under	
09/192,583	MOTOYAMA, TET	ETSURO	
Examiner	Art Unit		
CHUONG T. HO	2619		

SEARCHED					
Class	Subclass	Date	Examiner		
709	206	5/9/2008	СН		
709	224	5/9/2008	СН		
710	15	5/9/2008	СН		
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709	223	5/9/2008	СН		
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370	401,353	5/9/2008	СН		
370	353	5/9/2008	СН		

INTERFERENCE SEARCHED					
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709	206, 224	5/9/2008	СН		
370	401, 352	5/9/2008	СН		
370	353	5/9/2008	СН		
Text search of USPGPUB (see inter search history)		5/9/2008	СН		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
West (Text search, Class search) East IEEE STN	5/9/2008	СН		
Cosulting with Luu Le (Priamry Examiner AU 2141 (2-3884)	5/10/2008	СН		
Interviewed conference with Primary Examiner Philip Tran AU 2155 (2- 3991)	5/10/2008	СН		
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